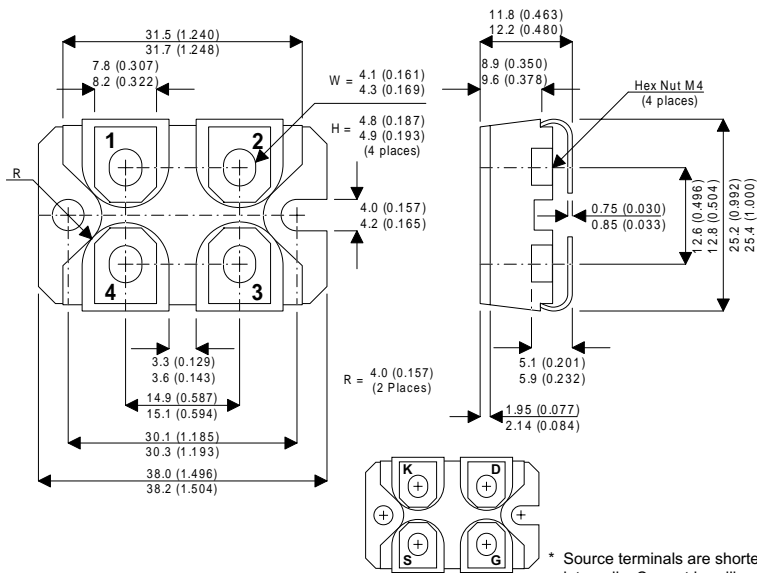


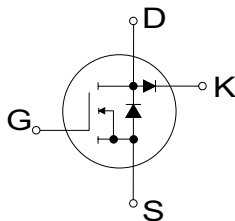
SOT-227 Package Outline.  
Dimensions in mm (inches)



**N-CHANNEL  
ENHANCEMENT MODE  
HIGH VOLTAGE  
POWER MOSFETS**

**$V_{DSS}$  500V**  
 **$I_{D(cont)}$  44A**  
 **$R_{DS(on)}$  0.100Ω**

- **Faster Switching**
- **Lower Leakage**
- **100% Avalanche Tested**
- **Popular SOT-227 Package**



\* Source terminals are shorted internally. Current handling capability is equal for either Source terminal.

StarMOS is a new generation of high voltage N-Channel enhancement mode power MOSFETs. This new technology minimises the JFET effect, increases packing density and reduces the on-resistance. StarMOS also achieves faster switching speeds through optimised gate layout.

**ABSOLUTE MAXIMUM RATINGS** ( $T_{case} = 25^{\circ}C$  unless otherwise stated)

$V_{DSS}$	Drain – Source Voltage	500	V
$I_D$	Continuous Drain Current	44	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	176	A
$V_{GS}$	Gate – Source Voltage	±30	V
$V_{GSM}$	Gate – Source Voltage Transient	±40	V
$P_D$	Total Power Dissipation @ $T_{case} = 25^{\circ}C$	450	W
	Derate Linearly	3.6	W/°C
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to 150	°C
$T_L$	Lead Temperature : 0.063" from Case for 10 Sec.	300	
$I_{AR}$	Avalanche Current <sup>1</sup> (Repetitive and Non-Repetitive)	44	A
$E_{AR}$	Repetitive Avalanche Energy <sup>1</sup>	50	mJ
$E_{AS}$	Single Pulse Avalanche Energy <sup>2</sup>	2500	

1) Repetitive Rating: Pulse Width limited by maximum junction temperature.

2) Starting  $T_J = 25^{\circ}C$ ,  $L = 2.89mH$ ,  $R_G = 25\Omega$ , Peak  $I_L = 30A$

**STATIC ELECTRICAL RATINGS** ( $T_{case} = 25^{\circ}C$  unless otherwise stated)

	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
$BV_{DSS}$	Drain – Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	500			V
$I_{DSS}$	Zero Gate Voltage Drain Current ( $V_{GS} = 0V$ )	$V_{DS} = V_{DSS}$			25	$\mu A$
		$V_{DS} = 0.8V_{DSS}, T_C = 125^{\circ}C$			250	
$I_{GSS}$	Gate – Source Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$			$\pm 100$	nA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 2.5mA$	2		4	V
$I_{D(ON)}$	On State Drain Current <sup>2</sup>	$V_{DS} > I_{D(ON)} \times R_{DS(ON)} \text{ Max}$ $V_{GS} = 10V$	44			A
$R_{DS(ON)}$	Drain – Source On State Resistance <sup>2</sup>	$V_{GS} = 10V, I_D = 0.5 I_D [\text{Cont.}]$			0.100	$\Omega$

**DYNAMIC CHARACTERISTICS**

	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input Capacitance	$V_{GS} = 0V$		7410		pF
$C_{oss}$	Output Capacitance	$V_{DS} = 25V$		1050		
$C_{rss}$	Reverse Transfer Capacitance	$f = 1MHz$		390		
$Q_g$	Total Gate Charge <sup>3</sup>	$V_{GS} = 10V$		312		nC
$Q_{gs}$	Gate – Source Charge	$V_{DD} = 0.5 V_{DSS}$		37		
$Q_{gd}$	Gate – Drain (“Miller”) Charge	$I_D = I_D [\text{Cont.}] @ 25^{\circ}C$		127		
$t_{d(on)}$	Turn-on Delay Time	$V_{GS} = 15V$		18		ns
$t_r$	Rise Time	$V_{DD} = 0.5 V_{DSS}$		16		
$t_{d(off)}$	Turn-off Delay Time	$I_D = I_D [\text{Cont.}] @ 25^{\circ}C$		54		
$t_f$	Fall Time	$R_G = 0.6\Omega$		5		

**SOURCE – DRAIN DIODE RATINGS AND CHARACTERISTICS**

	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
$I_S$	Continuous Source Current	(Body Diode)			44	A
$I_{SM}$	Pulsed Source Current <sup>1</sup>	(Body Diode)			176	
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	$V_{GS} = 0V, I_S = -I_D [\text{Cont.}]$			1.3	V
$t_{rr}$	Reverse Recovery Time	$I_S = -I_D [\text{Cont.}], di_S / dt = 100A/\mu s$		620		ns
$Q_{rr}$	Reverse Recovery Charge	$I_S = -I_D [\text{Cont.}], di_S / dt = 100A/\mu s$		14.7		$\mu C$

**THERMAL CHARACTERISTICS**

	Characteristic	Min.	Typ.	Max.	Unit
$R_{\theta JC}$	Junction to Case			0.28	$^{\circ}C/W$
$R_{\theta JA}$	Junction to Ambient			40	

1) Repetitive Rating: Pulse Width limited by maximum junction temperature.

2) Pulse Test: Pulse Width < 380 $\mu s$ , Duty Cycle < 2%

3) See MIL–STD–750 Method 3471



CAUTION — Electrostatic Sensitive Devices. Anti-Static Procedures Must Be Followed.